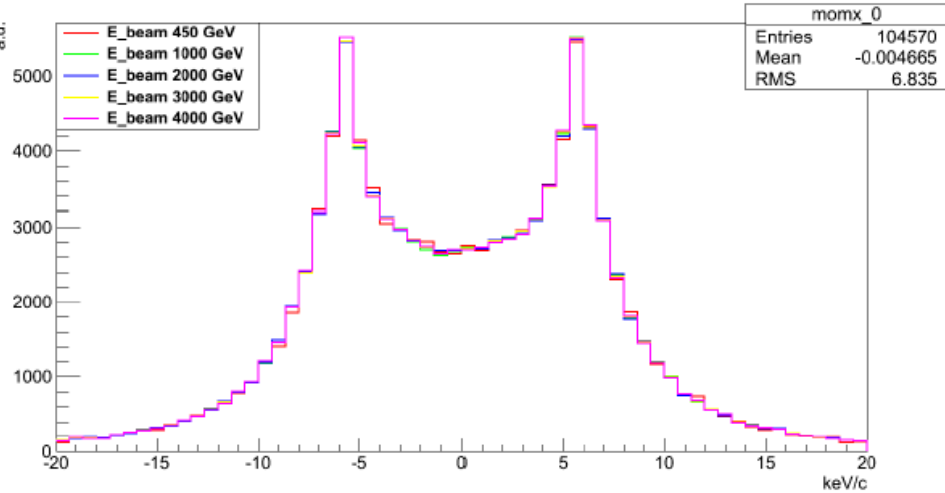


Bernd Dehning
CERN BE/BI

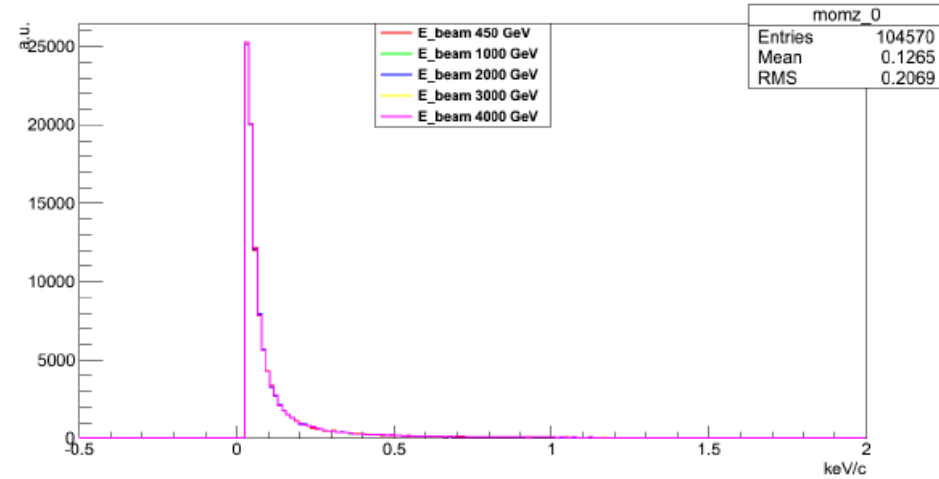
- Ionisation profile monitors
 - Marcin PATECKI : Electron tracking simulations in the presence of beam and external fields
 - Randy THURMAN-KEUP: IPM EM simulations
 - Jacques MARRONCLE: IPM developments for IFMIF
- Luminescence monitors and Gas jets
 - Peter FORCK: Experience with Luminescence monitors at GSI
 - Thomas TSANG: Experience with hydrogen gas jet and residual gas monitors at BNL-RHIC
 - Adam JEFF: Gas Jet Monitors

Electron momentum distribution

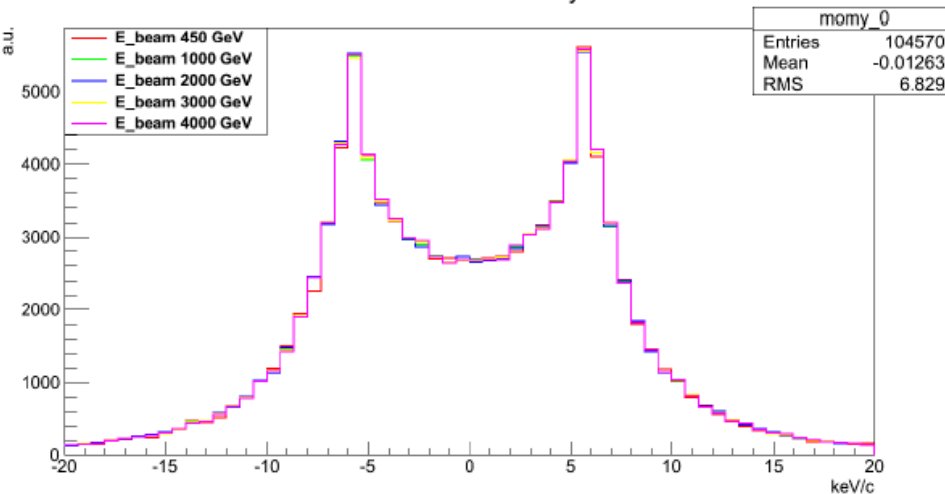
e momentum distribution in x direction



e momentum distribution in z direction



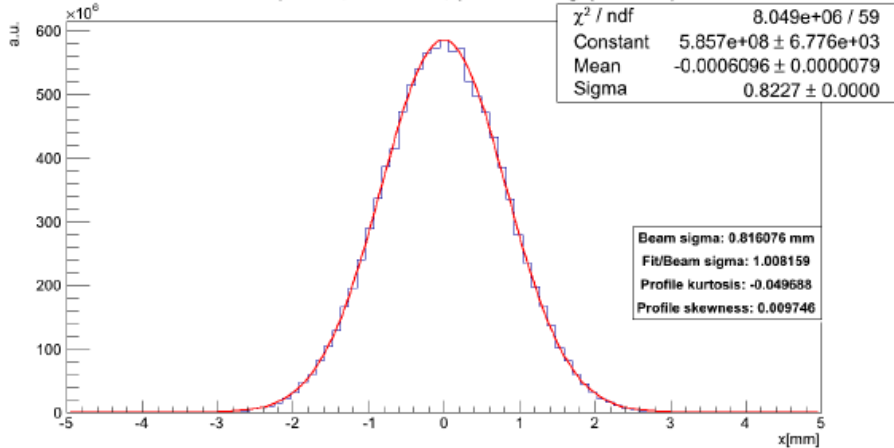
e momentum distribution in y direction



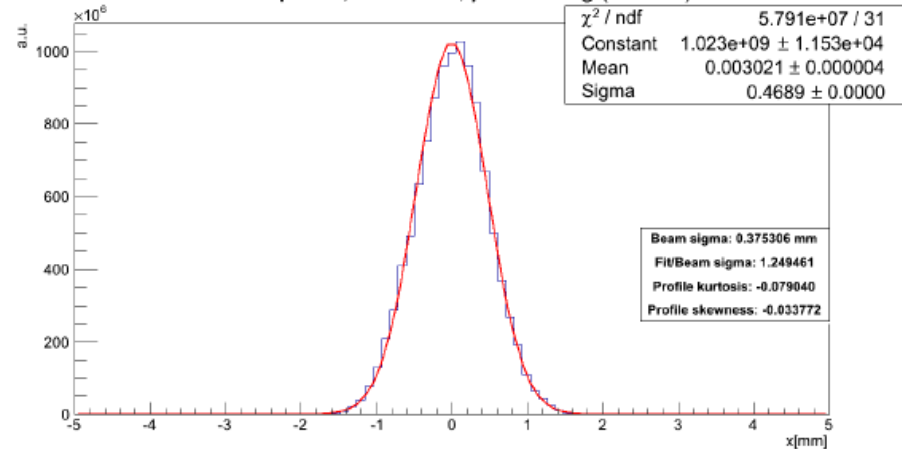
- No energy dependence;
- The same distribution in x and y direction;
- Significantly lower momentum in longitudinal direction.

Initial momentum effect

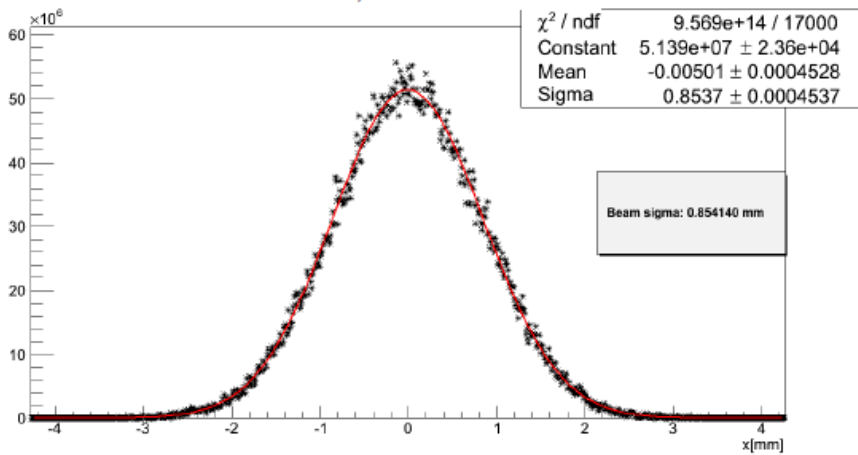
Beam profile, 450 GeV, pixelbinning (110 um)



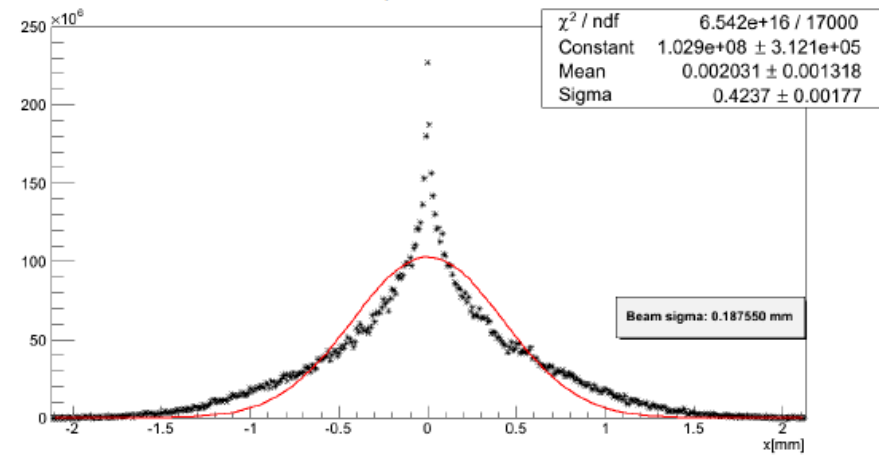
Beam profile, 4000 GeV, pixelbinning (110 um)



450 GeV, 0 e momentum

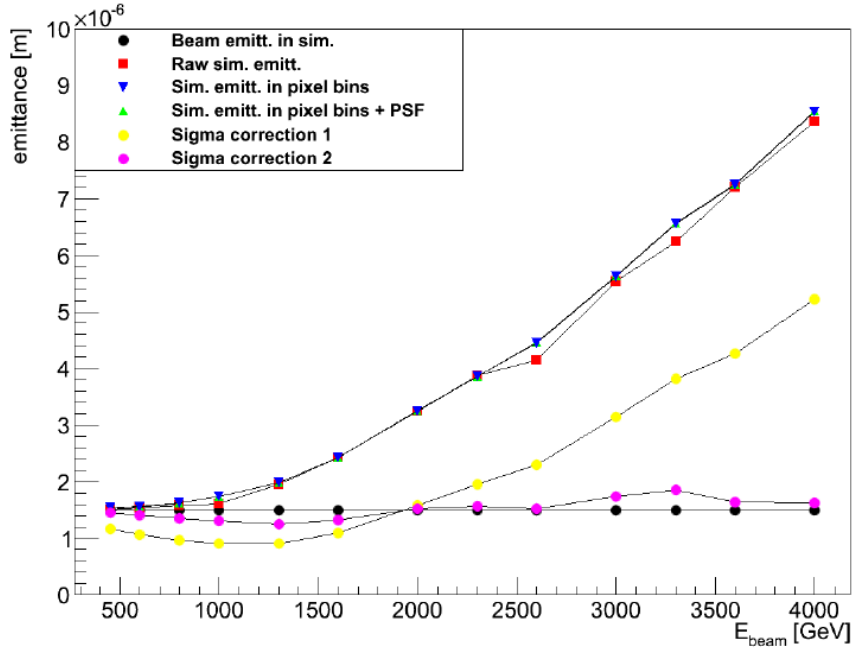


4000 GeV, 0 e momentum

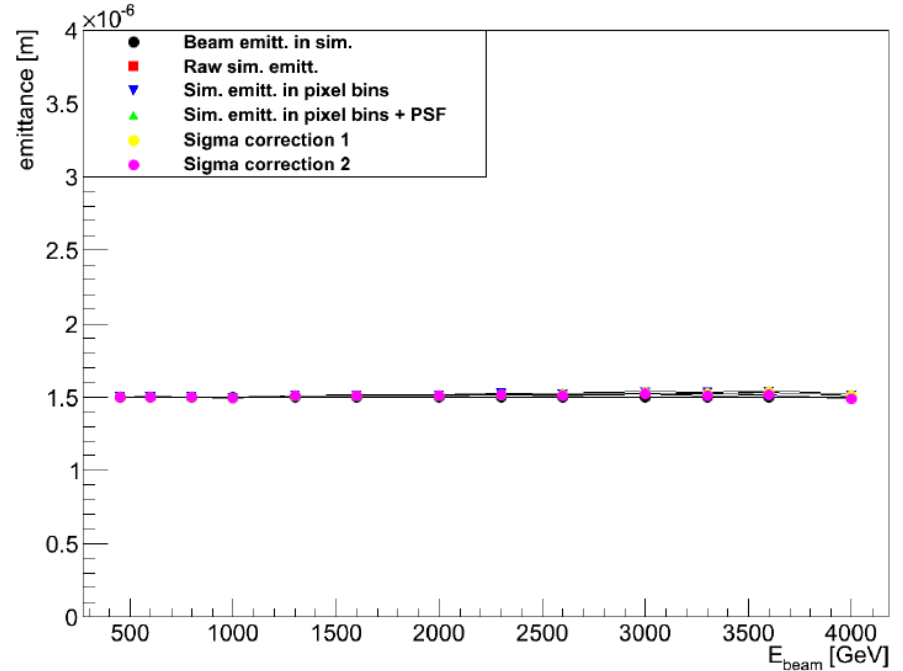


Emittance and Space Charge 0.2 T and 1T

$\sigma_z = 1.1$ ns, $I = 1.65 \times 10^{11}$ p/bunch

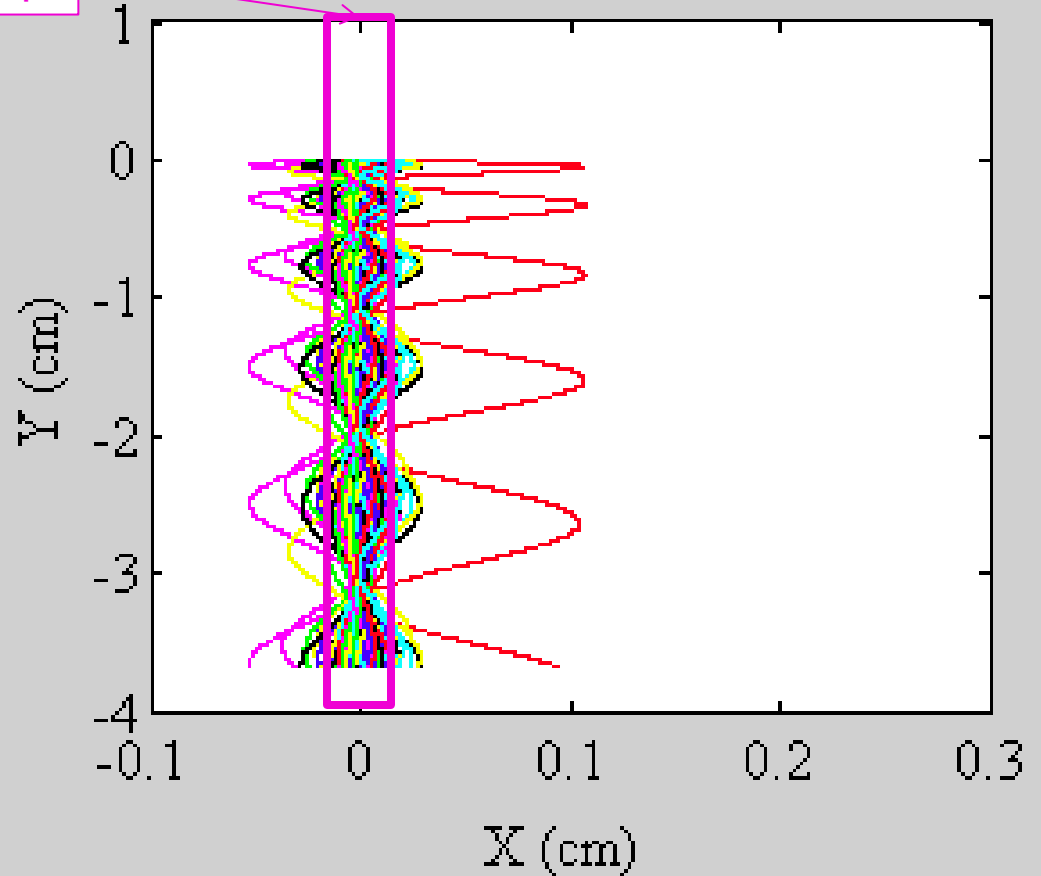


$\sigma_z = 1.1$ ns, $I = 1.65 \times 10^{11}$ p/bunch



Gated-on IPM

Anode Strip



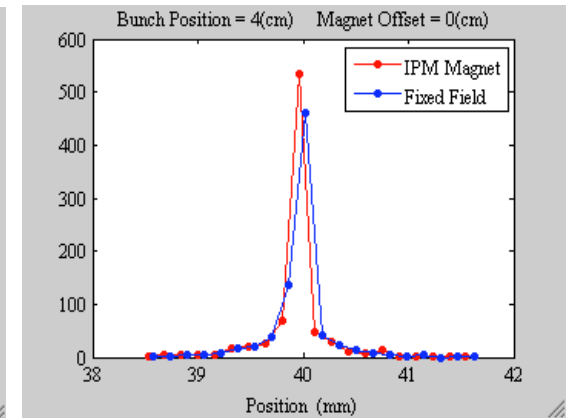
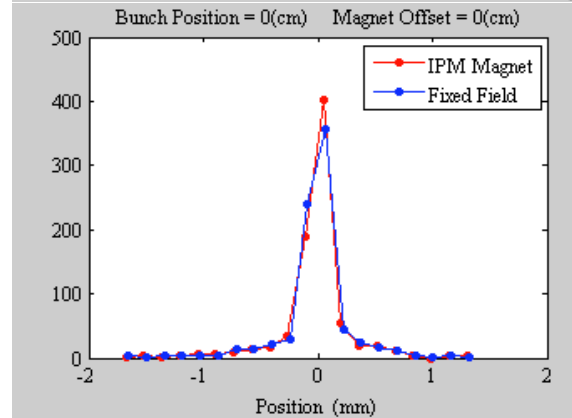
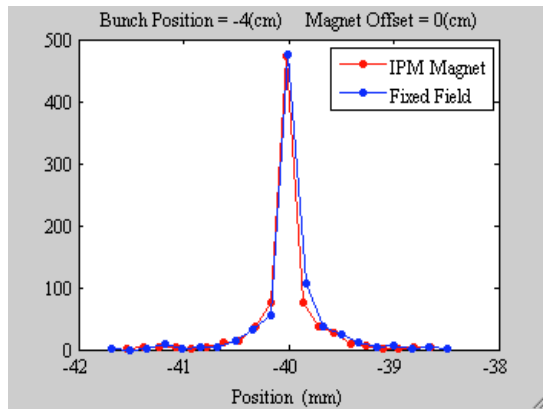
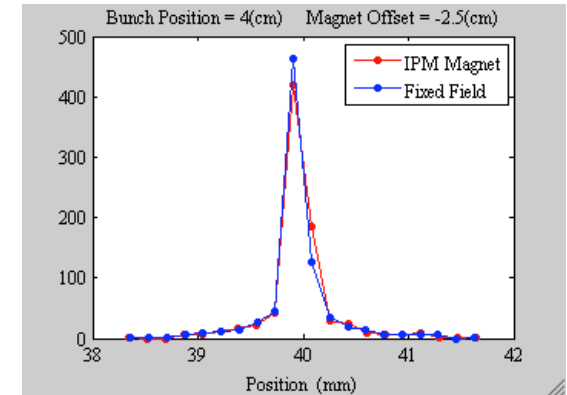
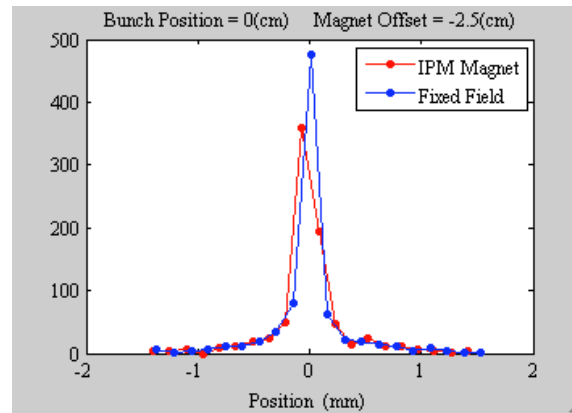
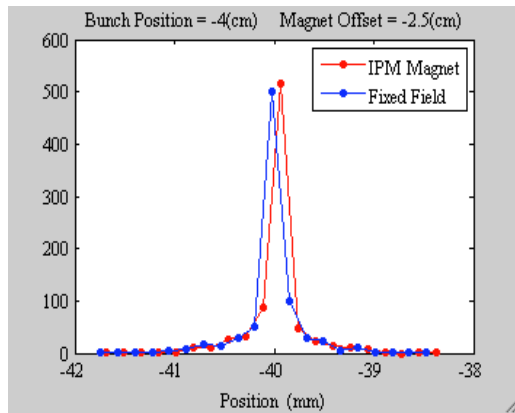
Particles originating
from single point
(resolution
contribution)

Elapsed time ~ 1.7 ns

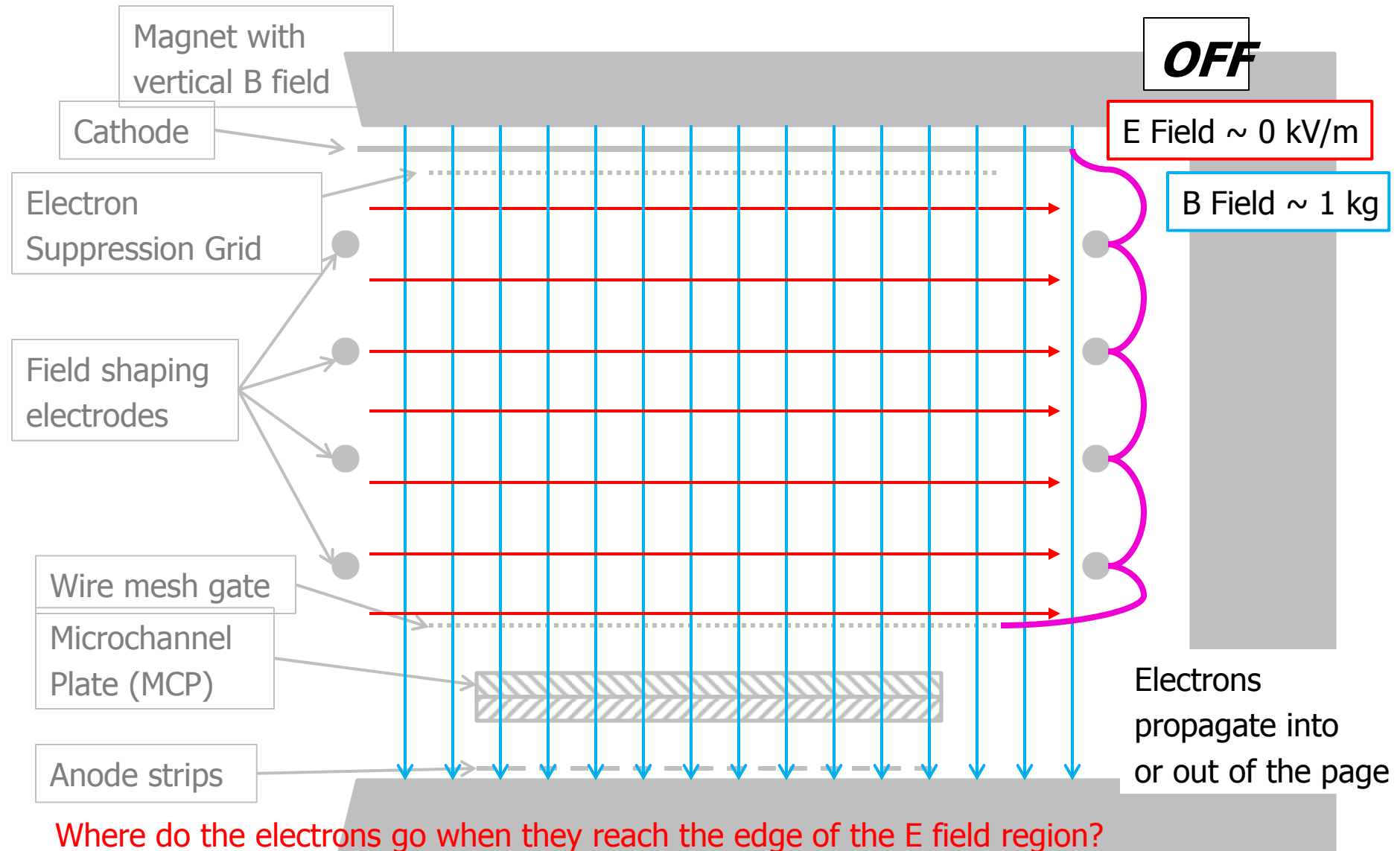
Gated-on IPM

Particles originating from single point
(resolution contribution)

Bunch offset refers to x



Gated-off IPM



Where do the electrons go when they reach the edge of the E field region?

Need 3-D E field calculation

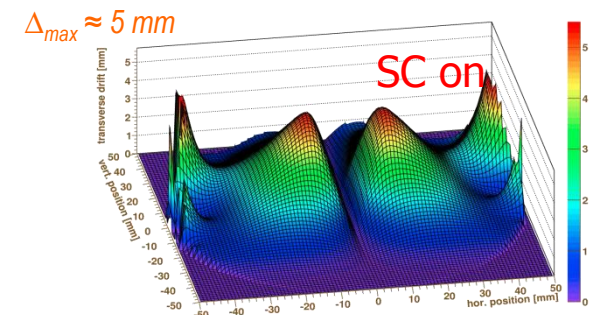
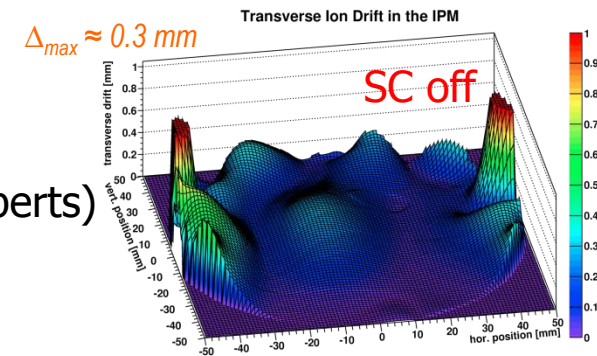
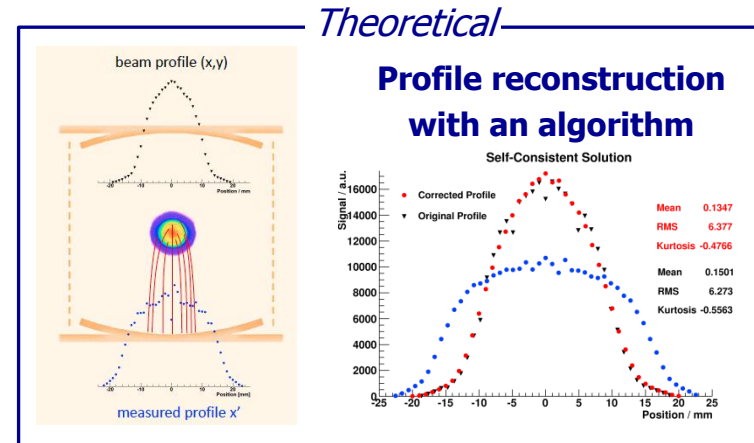
Space Charge effect

Ionization products experienced

- IPM electric field
- Beam electric field: **Space Charge**
 - GSI: low I \Rightarrow negligible effect
 - IPHI: high I, low E \Rightarrow big effect (profile distortion)

How to counteract SC

- magnetic field for guidance \rightarrow no space available
- increasing the electric field \rightarrow limitation due to deviation
- applying correction with an algorithm (developed by Jan Egberts)



Space Charge Algorithm

1- Hypothesis

- D⁺
- round beam
- beam charge distribution described by a generalized Gaussian Distribution (GGD)
- I_{beam}

2- Approach

$$\vec{P}_{\text{Corrected}} = \mathbf{M} \times \vec{P}_{\text{Measured}}$$

- Matrix components M_{ij} represent the probability that an ion collected on strip j has been create at the position i
→ beam distribution (GGD) & ions trajectories
- Set of matrices computed for various parameter combinations

I_{beam}: 1 to 125 mA → 35

σ: 5 to 15 mm → 21

β: -0.25 to 0.25 → 3

total matrices: 2205

3- First parameter to initiate iteration process

- fit of the experimental profile using a GGD to **extract**

I_{beam}: given by Current Transformers

→ σ₀ = σ_{exp}

→ β₀ = β_{exp}

- iterations $\vec{P}_1 = \mathbf{M}(s_{\text{exp}}, b_{\text{exp}}) \times \vec{P}_{\text{Measured}} \supset s_1$ and b_1 extraction from \vec{P}_1 fit

$\vec{P}_2 = \mathbf{M}(s_1, b_1) \times \vec{P}_1 \supset s_2$ and b_2 extraction from \vec{P}_2 fit

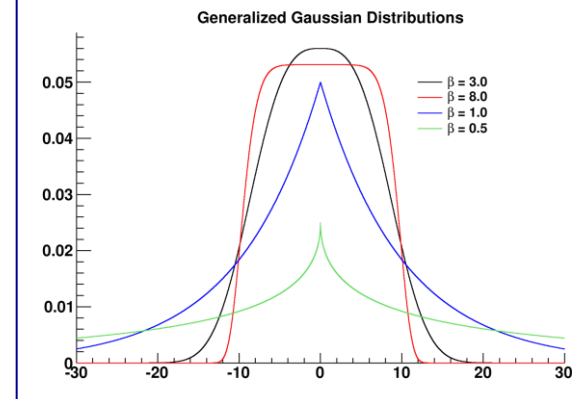
$\vec{P}_n = \mathbf{M}(s_{n-1}, b_{n-1}) \times \vec{P}_{n-1} \supset s_n$ and b_n extraction from \vec{P}_n fit

until parameters converge (σ_n ≈ σ_{n-1} ; β_n ≈ β_{n-1}) → self consistent solution

Generalized Gaussian distribution

- μ: profile center
- Two degrees of freedom
- σ: 2nd moment
- β: kurtosis, 4th moment

$$p_{a,b,m}(x) = \frac{b}{2a\Gamma(1/b)} e^{-\frac{|x-\mu|}{a}} e^{-\frac{|x-\mu|^m}{b}}$$



IPM: HEBT

Large aperture: $15 \times 15 \text{ cm}^2$

Very high radiation background: 7 kSv/h neutrons on beam axis

⇒ Materials: ceramics (RO4350B), copper, resistors (CMS), Kapton (ribbon cable)
+ SAMTEC 80 micro coaxial cables (PVC, LCP, FEP ; halogen)

Degraders (16×2): $230 \text{ M}\Omega$ → Lorentz-3D for electric field uniformity

FEE based on integrators; rate $\approx 10 \text{ Hz}$

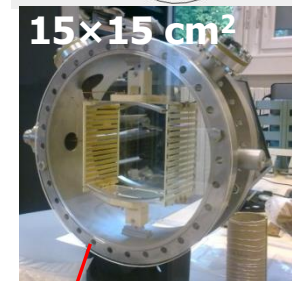
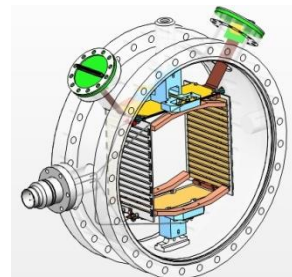
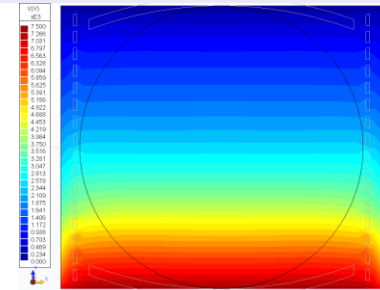
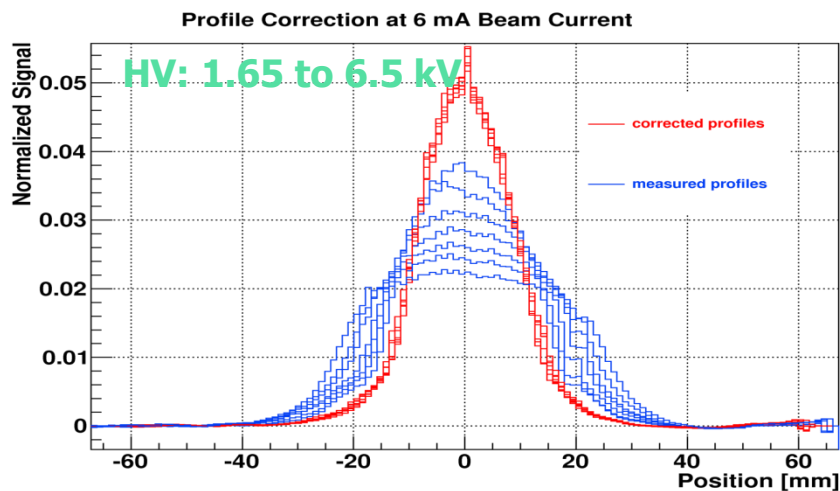
$HV_{\text{max}} = 16 \text{ kV}$

Tests done at Saclay on SILHI source: Dec. 2011 - Feb. 2012

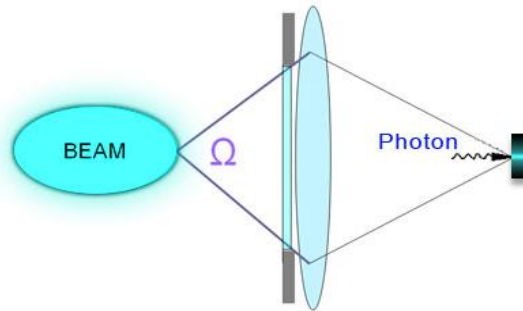
proton $E_{\text{max}} = 95 \text{ keV}$, $I_{\text{max}} = 100 \text{ mA}$, dc: up to cw

Main test: SC algorithm

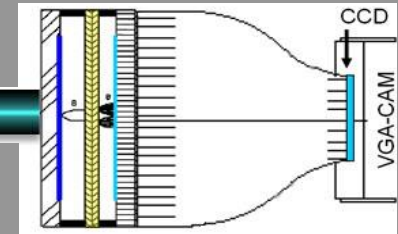
- frozen beam characteristics (conditions)
- only variation of extracting field



GSI: Peter Fork: **Shielding Concept for Background Reduction**



Effective neutron shielding:
moderation and absorption



← e.g. 0.5 m concrete →

FLUKA simulation:

Shielding of 1x1x1 m³ concrete block:

900 MeV/u BIF monitor 2m to beam dump

⇒ γ & n reduction 95 %

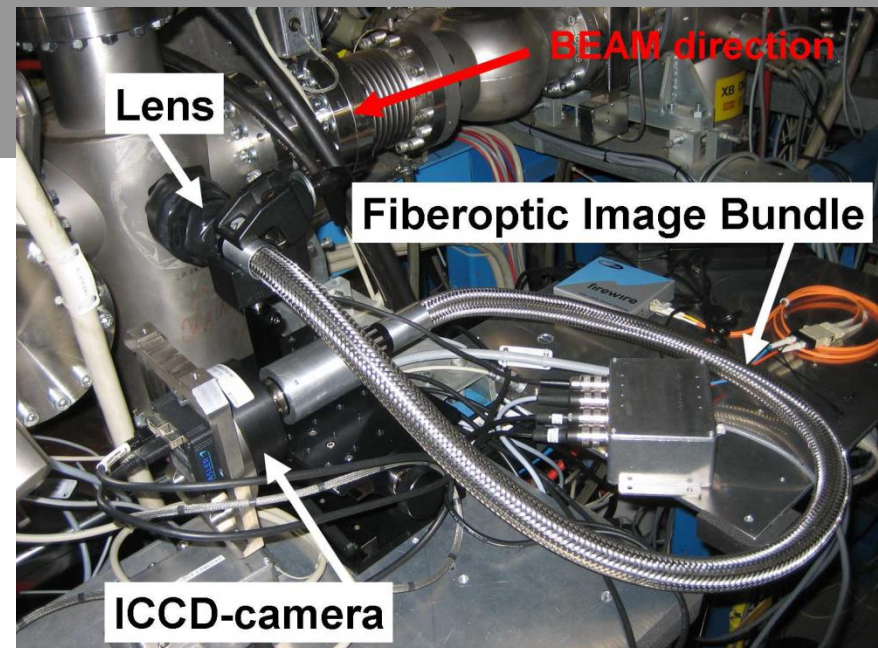
Fiber-optic bundle with ≈ 1 million fibers:

- Commercial device for reduction of background and CCD destruction
- Image Intensifier and CCD in shielded area
- larger distance but same solid angle

Experimental results:

- No significant image distortion
- Low scintillation by n & γ inside bundle

un-shielded: ≈ 30 % increase of background



GSI: Peter Fork: Spectroscopy – Variation of Gas Pressure

Task: To which pressure the methods delivers a correct profile reproduction?

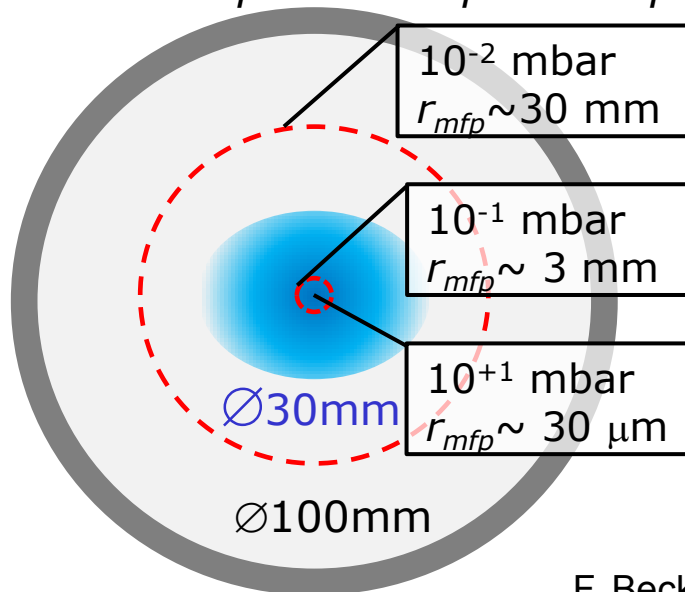
Investigated: 10^{-3} mbar $< p < 100$ mbar

Secondary electron might excite residual gas:

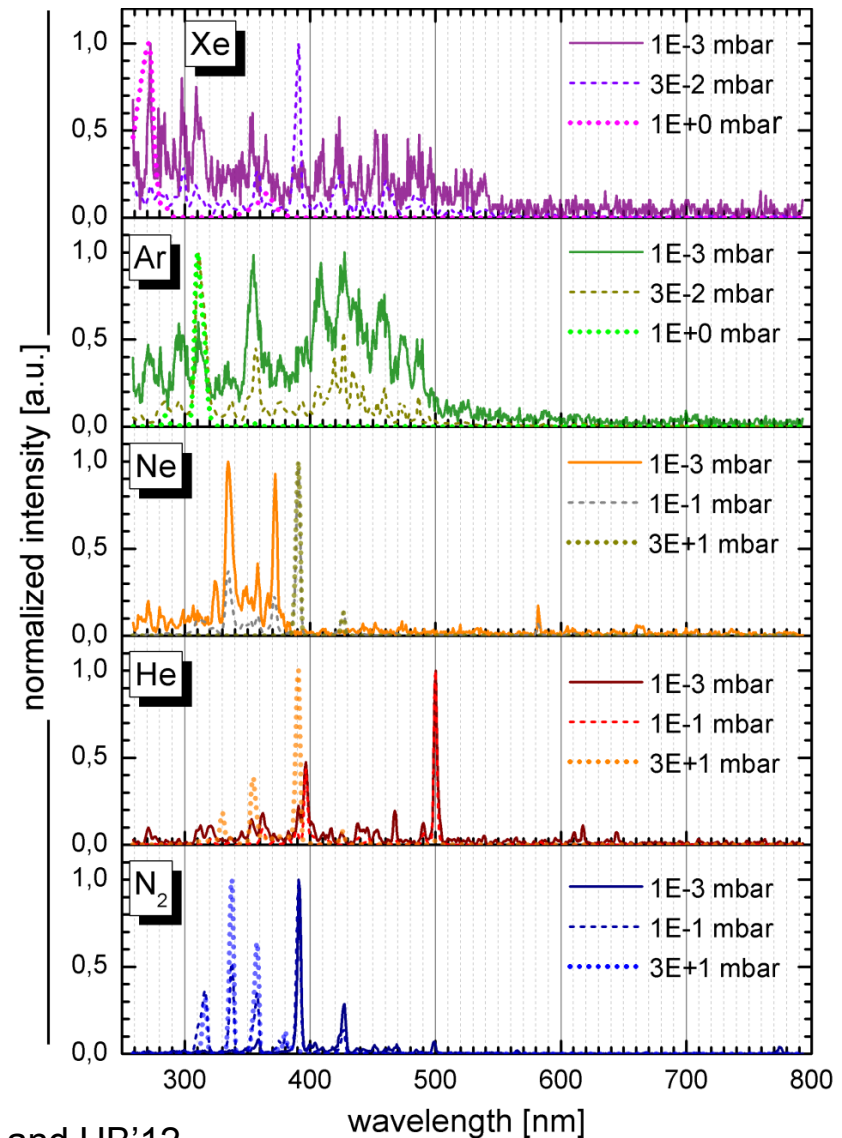
⇒ mean free path at 10^{-3} mbar: $r_{mfp} \gg r_{beam}$

⇒ mean free path at 10 mbar: $r_{mfp} \ll r_{beam}$

Observation: pressure dependent spectrum

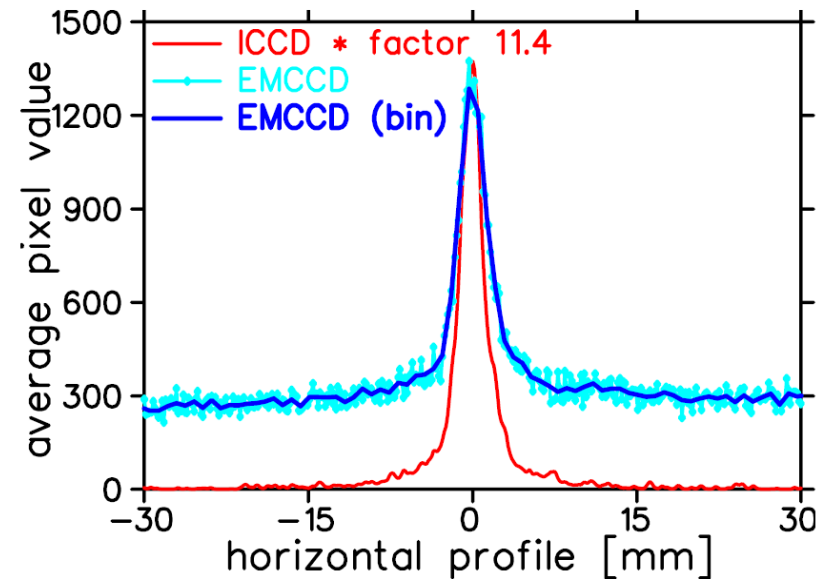
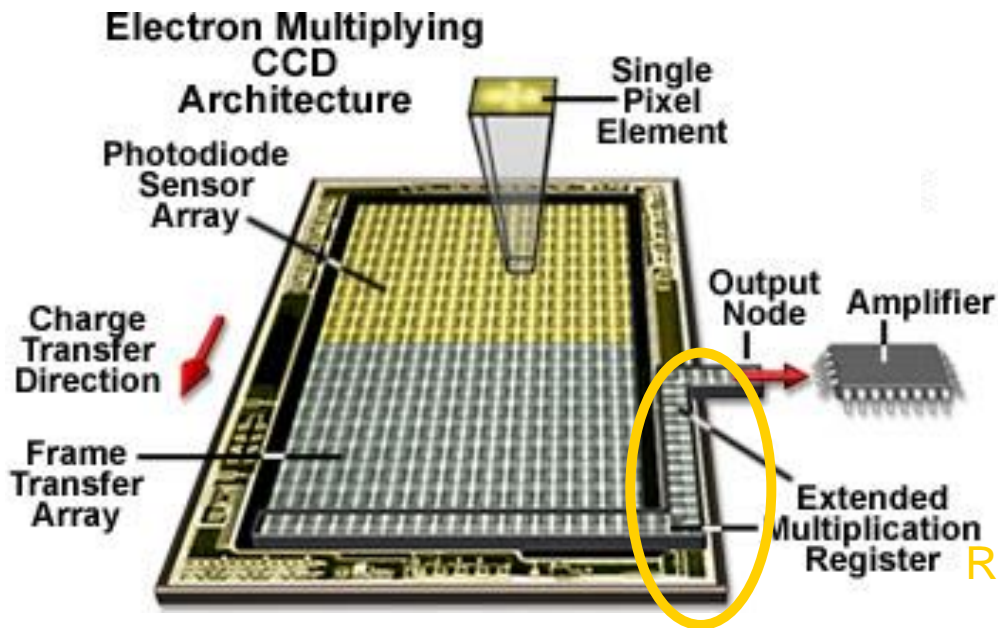


Beam: S at 3 MeV/u at TU-München TANDEM



GSI: Peter Fork: Alternative Single Photon Camera: emCCD

Principle of electron multiplication CCD:



Results: Suited for single photon detection
 x5 higher spatial resolution as ICCD
 more noise due to electrical amplification
 ⇒ Acts as an alternative

Multiplication by avalanche diodes:

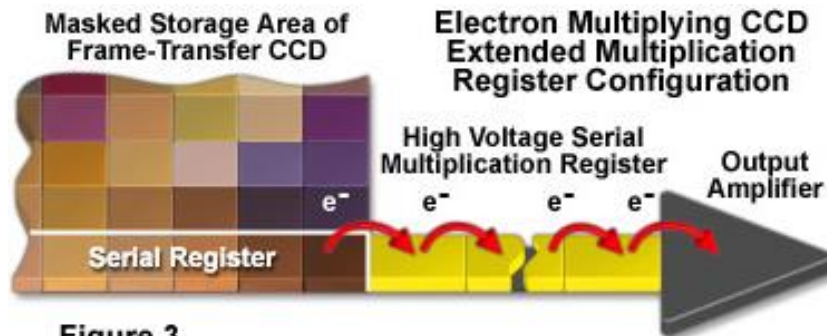


Figure 3

Parameter of Hamamatsu C9100-13

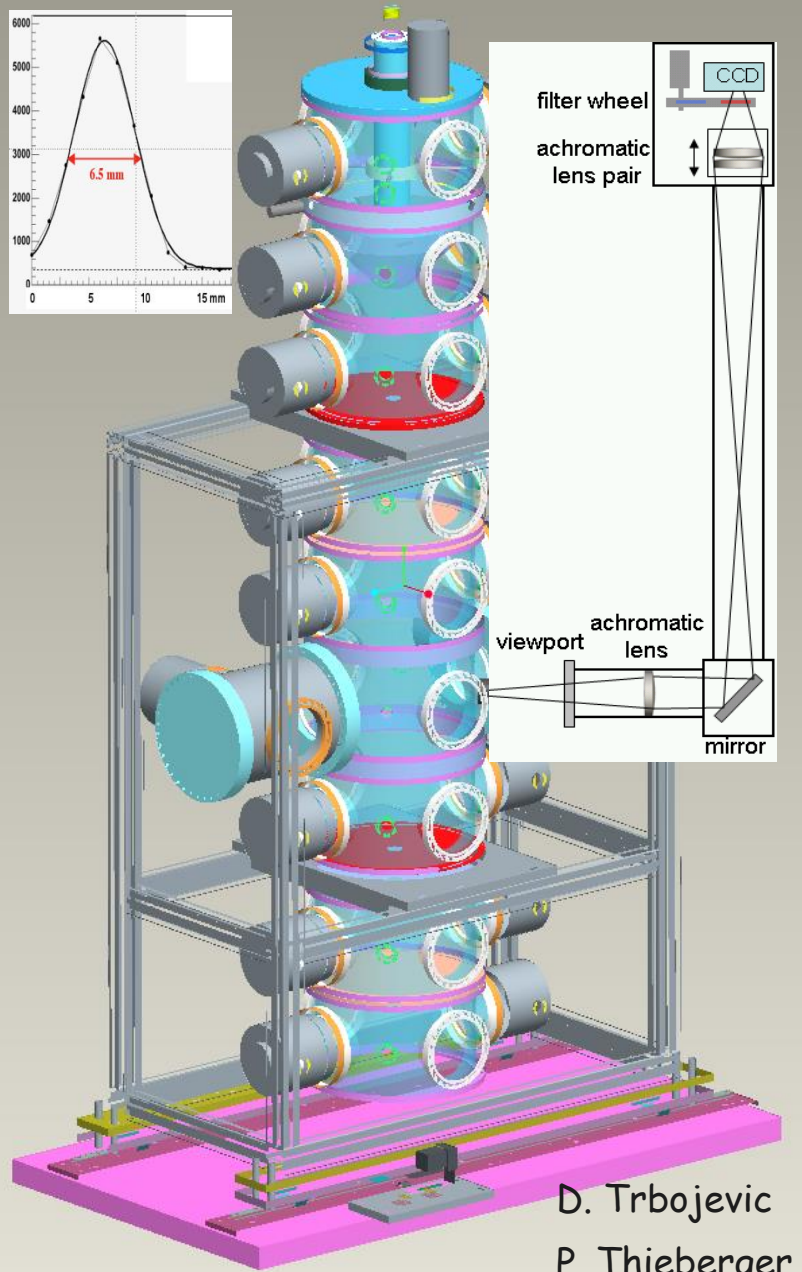
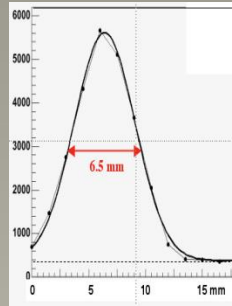
Pixel: 512x512, size $16 \times 16 \mu\text{m}^2$

Maximum amplification: x1200

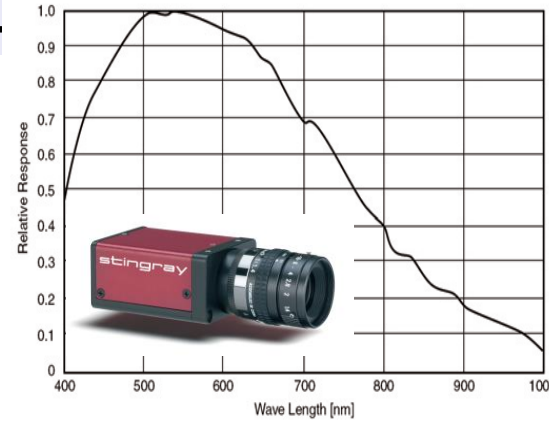
Temperature of emCCD sensor: -80°C

Readout noise: about $1 e^-$ per pixel

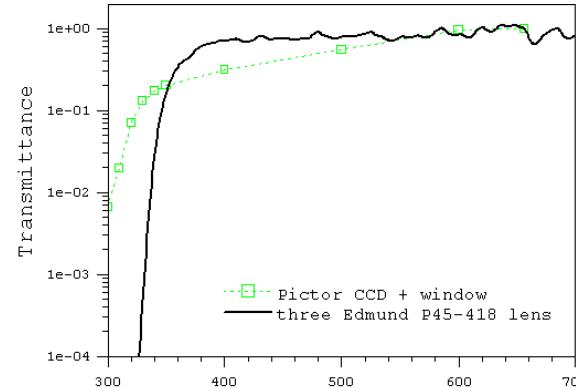
BNL: Thomas Tsang: The imaging system



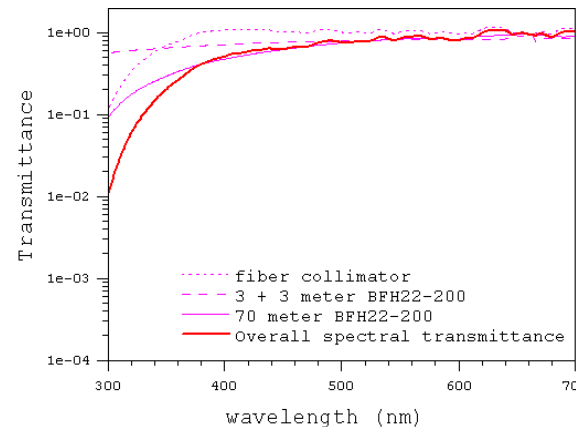
D. Trbojevic
P. Thieberger



AVT Stingray F-145B/fiber
Sony ICX-285 CCD
1394b 800Mb fiber
1388 X 1038, 6.45um pixels
8, 12, 16-bit ADC
Exposure: 73 μ s to 67sec



Transmittance
of achromat lens



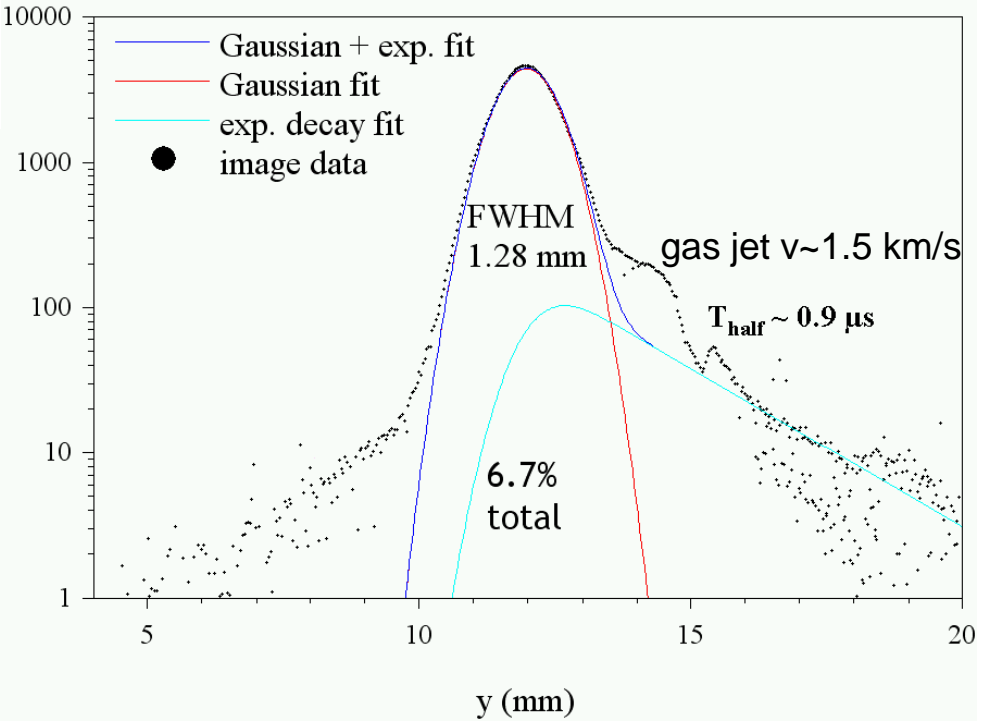
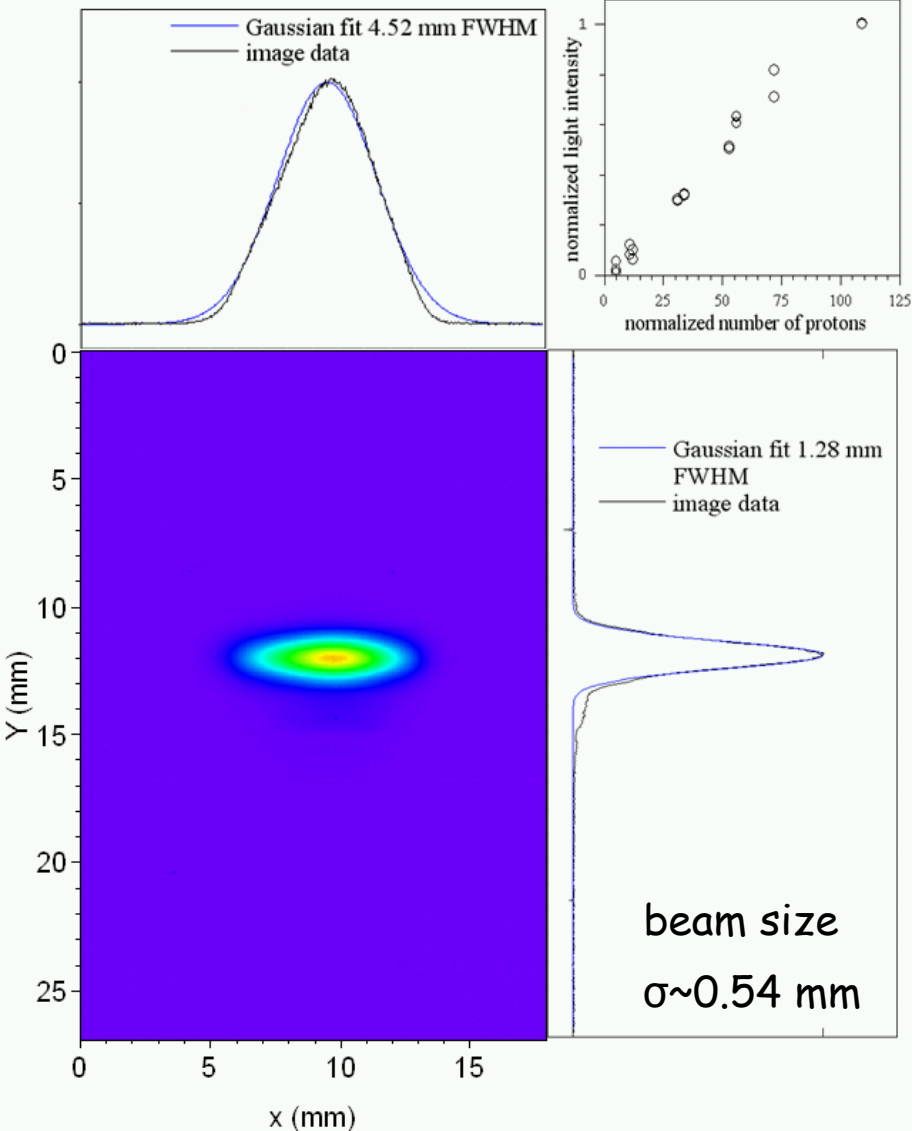
transmittance of
fiber collimator and
70 meter BFH22-200 fiber

Overall (650 nm)
View solid angle: 1.4×10^{-3} sr
Optics:throughput: 0.58

BNL: Thomas Tsang: Proton Beam and H-Jet beam size

100 GeV

H-jet beam width $\times \sqrt{2} \sim 6.4$ mm



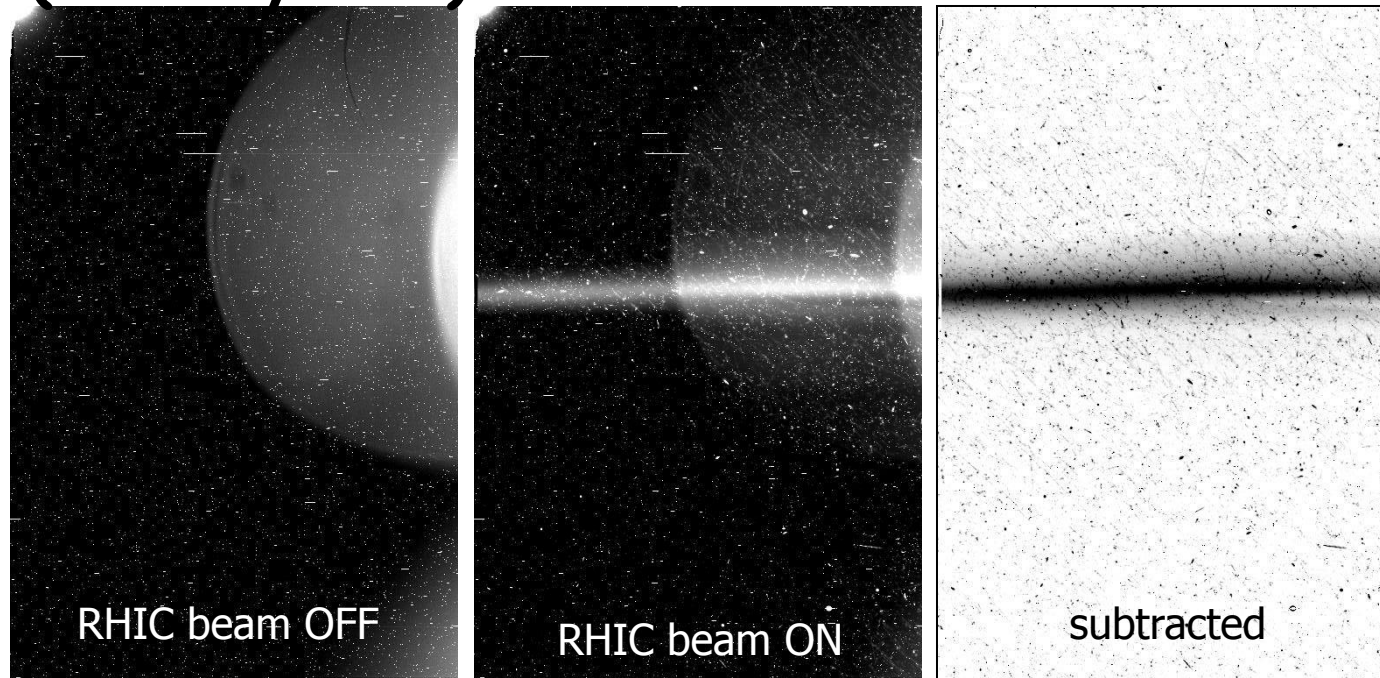
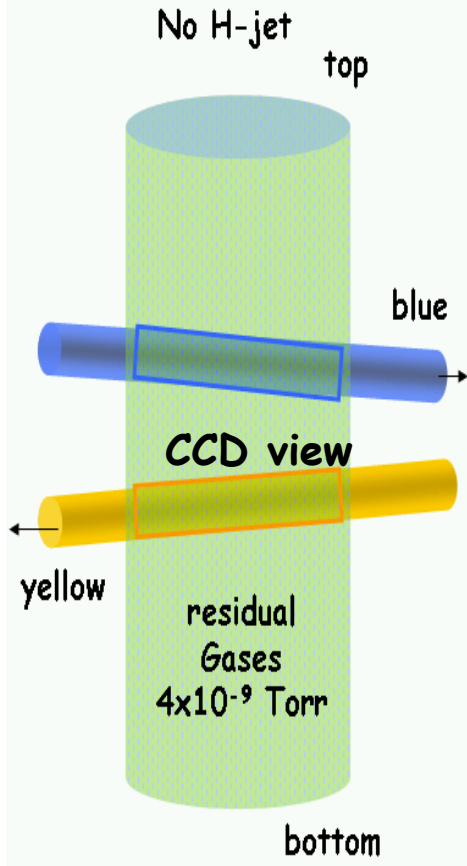
Reveals the lifetime of a metastable state of Hydrogen, $0.9 \mu\text{s}$ lifetime

Fluorescence lifetime remains @ 10-20 ns

An image provides many information of

Dec. 2, 2007

Deuteron-Au ion, 100 GeV/n, 69+69 bunch
(blue - yellow)



no spectral filter, a few min. exposure

streak of Au ion fluorescence was observed
none for deuteron

BNL: Thomas Tsang: RGFM - ion beam summary

Modes	U-U ions		Cu-Au ions	
	U-Blue	U-Yellow	Cu - Blue	Au - Yellow
RHIC beam	U-Blue	U-Yellow	Cu - Blue	Au - Yellow
beam width, σ (mm)	0.26	0.24	0.37	0.36
vertical emittance ϵ (π mm mrad)	5.7-12.5	5.6-11.0	14-27	18-22
Fluorescence cross-section (cm^2)	2.6×10^{-16}		1.8×10^{-17}	2.1×10^{-16}

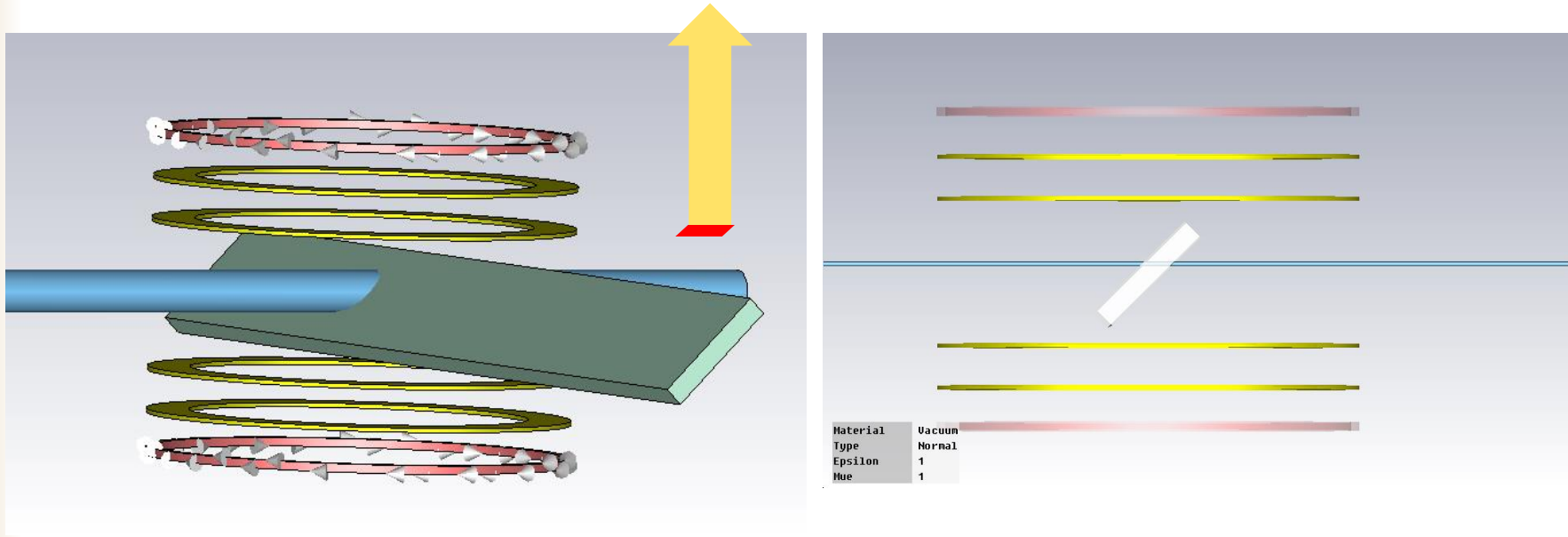
cross-section obeys the Z^2 dependence: Bethe-Block law

- provide simple visual inspection of beam
- hydrogen is the dominant residue gas constituent in all vacuum system
- RGFM is a passive, robust, truly *noninvasive* beam monitor
- beam-induced fluorescence is a weak process (1 bunch 3×10^8 U-ion gives ~ 7 photons)
- need longer exposure time to capture high s/n image
- need to monitor both vertical and horizontal planes
- need to avoid long term radiation damage to equipment

CRN: Adam Jeff: Principle of the Gas Jet Monitor



- Gas jet shaped into a plane inclined at 45° to beam
- Extract ions or electrons perpendicularly
- Collect on phosphor / MCP and image
- Gas jet collected on opposite side of beam pipe
- Resolution depends on jet thickness



Gas jet monitors are an interesting option for many accelerators and have significant advantages over traditional residual-gas monitors.

The added cost of the gas jet system is offset by measurement of both profiles at once.

Gas jets have been used over a huge range of intensities:

	Jet material	Jet pressure (Torr)	Jet thickness	Accelerator Vacuum (Torr)
ISR, CERN	Sodium Vapour	10^{-5}	0.7mm	10^{-9}
Los Alamos	Hydrogen	10	2-4 mm	10^{-5}
LEAR, CERN	Carbon	5×10^{-10}	1-5mm	10^{-12}
HIMAC, KEK	Oxygen	10^{-7}	1.3mm	10^{-11}
RHIC, BNL	Hydrogen	10^{-8}	10mm	10^{-10}
USR, FLAIR	?	?	?	10^{-11}
CLIC Drive Beam	?	?	?	10^{-9}

Some questions for discussion I

- LHC IPM limitation
 - Space charge effect
 - Mitigation:
 - increase B-field, CERN
 - Use correction: IFMIF
 - Camera system sensitivity to EMC
 - Mitigation:
 - Digital cameras (GSI)
 - Calibration of system
 - Mitigation
 - Electron emission plate (CERN, FNAL)
 - Calibrate electronic strips by capacitive test signal coupling (BNL, FNAL)
 - Use signal and optimise gain (move MCP or beam), application possible for strip and MCP possible

Some questions for discussion II

- New continuous emittance monitor for the PS
 - Condition:
 - Relative high vacuum $\sim e-8$, (pressure bump possible)
 - Revolution period 6 us
 - Energy 1 to 26 GeV
 - Up few E13 intensity
 - Limited longitudinal space available
 - Dose in the order 100 to 1000 Gy / year
 - Beam size changes during ramp
 - Required accuracy relative ($\Delta \sigma / \sigma$) few %
 - Calibration of system is possible with wire scanners =>
Main requirement high reproducibility
- Options:
 - IPM (Using a gas jet?)
 - Luminescence (Using a gas jet?)
 - Beam scanner
 - Imaging by optical or strip system (Si detectors)
 - How to overcome the radiation effect
 - Usage of radiation tolerant preamplifiers (FNAL)
 - Usage of telescope or optical light guide (GSI)